

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination EATON ET AL.	
		Examiner SIMON D. NGUYEN	Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2003/0033385	02-2003	Yavitz, Edward Q.	709/219
*	B US-2002/0056093	05-2002	Kunkel et al.	725/35
*	C US-5,897,623	04-1999	Fein et al.	705/27
*	D US-6,396,546	05-2002	Allen et al.	348/569
*	E US-6,097,441	08-2000	Allport, David E.	348/552
*	F US-6,209,028	03-2001	Walker et al.	709/219
*	G US-6,275,989	08-2001	Broadwin et al.	725/37
*	H US-6,323,911	11-2001	Schein et al.	348/552
*	I US-6,061,719	05-2000	Bendinelli et al.	709/218
*	J US-6,545,722	04-2003	Schultheiss et al.	348/552
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
O					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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V		
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X		

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